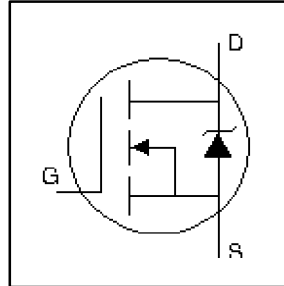


### HEXFET® Power MOSFET

- Surface Mount
- Available in Tape & Reel
- Dynamic dv/dt Rating
- Repetitive Avalanche Rated
- Logic-Level Gate Drive
- $R_{DS(ON)}$  Specified at  $V_{GS} = 4V$  &  $5V$
- $150^{\circ}C$  Operating Temperature



$$V_{DSS} = 200V$$

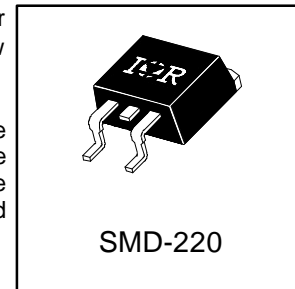
$$R_{DS(on)} = 0.40\Omega$$

$$I_D = 9.0A$$

### Description

Third Generation HEXFETs from International Rectifier provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The SMD-220 is a surface mount power package capable of accommodating die sizes up to HEX-4. It provides the highest power capability and the lowest possible on-resistance in any existing surface mount package. The SMD-220 is suitable for high current applications because of its low internal connection resistance and can dissipate up to 2.0W in a typical surface mount application.



### Absolute Maximum Ratings

	Parameter	Max.	Units
$I_D$ @ $T_C = 25^{\circ}C$	Continuous Drain Current, $V_{GS}$ @ 5.0V	9.0	A
$I_D$ @ $T_C = 100^{\circ}C$	Continuous Drain Current, $V_{GS}$ @ 5.0V	5.7	
$I_{DM}$	Pulsed Drain Current ①	36	
$P_D$ @ $T_C = 25^{\circ}C$	Power Dissipation	74	W
$P_D$ @ $T_C = 25^{\circ}C$	Power Dissipation (PCB Mount)**	3.1	
	Linear Derating Factor	0.59	W/ $^{\circ}C$
	Linear Derating Factor (PCB Mount)**	0.025	
$V_{GS}$	Gate-to-Source Voltage	$\pm 10$	V
$E_{AS}$	Single Pulse Avalanche Energy ②	250	mJ
$I_{AR}$	Avalanche Current ①	9.0	A
$E_{AR}$	Repetitive Avalanche Energy ①	7.4	mJ
dv/dt	Peak Diode Recovery dv/dt ③	5.0	V/ns
$T_J, T_{STG}$	Junction and Storage Temperature Range	-55 to + 150	$^{\circ}C$
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	

### Thermal Resistance


	Parameter	Min.	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	—	—	1.7	$^{\circ}C/W$
$R_{\theta JA}$	Junction-to-Ambient (PCB Mount)**	—	—	40	
$R_{\theta JA}$	Junction-to-Ambient	—	—	62	

\*\* When mounted on 1" square PCB (FR-4 or G-10 Material).  
For recommended footprint and soldering techniques refer to application note #AN-994.

# IRL630S



## Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	200	—	—	V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.27	—	V/ $^\circ\text{C}$	Reference to $25^\circ\text{C}, I_D = 1\text{mA}$
$R_{DS(ON)}$	Static Drain-to-Source On-Resistance	—	—	0.40	$\Omega$	$V_{GS} = 5.0V, I_D = 5.4A$ ①
		—	—	0.50		$V_{GS} = 4.0V, I_D = 4.5A$ ②
$V_{GS(th)}$	Gate Threshold Voltage	1.0	—	2.0	V	$V_{DS} = V_{GS}, I_D = 250\mu A$
$g_{fs}$	Forward Transconductance	4.8	—	—	S	$V_{DS} = 50V, I_D = 5.4A$
$I_{DSS}$	Drain-to-Source Leakage Current	—	—	25	$\mu A$	$V_{DS} = 200V, V_{GS} = 0V$
		—	—	250		$V_{DS} = 160V, V_{GS} = 0V, T_J = 125^\circ\text{C}$
$I_{GSS}$	Gate-to-Source Forward Leakage	—	—	100	nA	$V_{GS} = 10V$
	Gate-to-Source Reverse Leakage	—	—	-100		$V_{GS} = -10V$
$Q_g$	Total Gate Charge	—	—	40	nC	$I_D = 9.0A$
$Q_{gs}$	Gate-to-Source Charge	—	—	5.5		$V_{DS} = 160V$
$Q_{gd}$	Gate-to-Drain ("Miller") Charge	—	—	24		$V_{GS} = 10V$ , See Fig. 6 and 13 ④
$t_{d(on)}$	Turn-On Delay Time	—	8.0	—	ns	$V_{DD} = 100V$
$t_r$	Rise Time	—	57	—		$I_D = 9.0A$
$t_{d(off)}$	Turn-Off Delay Time	—	38	—		$R_G = 6.0\Omega$
$t_f$	Fall Time	—	33	—		$R_D = 11\Omega$ , See Fig. 10 ④
$L_D$	Internal Drain Inductance	—	4.5	—	nH	Between lead, 6mm (0.25in.) from package and center of die contact
$L_S$	Internal Source Inductance	—	7.5	—		
$C_{ISS}$	Input Capacitance	—	1100	—	pF	$V_{GS} = 0V$
$C_{OSS}$	Output Capacitance	—	220	—		$V_{DS} = 25V$
$C_{RSS}$	Reverse Transfer Capacitance	—	70	—		$f = 1.0\text{MHz}$ , See Fig. 5

## Source-Drain Ratings and Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_S$	Continuous Source Current (Body Diode)	—	—	9.0	A	MOSFET symbol showing the integral reverse p-n junction diode.
$I_{SM}$	Pulsed Source Current (Body Diode) ①	—	—	36		
$V_{SD}$	Diode Forward Voltage	—	—	2.0	V	$T_J = 25^\circ\text{C}, I_S = 9.0A, V_{GS} = 0V$ ②
$t_{rr}$	Reverse Recovery Time	—	230	350	ns	$T_J = 25^\circ\text{C}, I_F = 9.0A$
$Q_{rr}$	Reverse Recovery Charge	—	1.7	2.6	$\mu C$	$di/dt = 100A/\mu s$ ③
$t_{on}$	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S + L_D$ )				

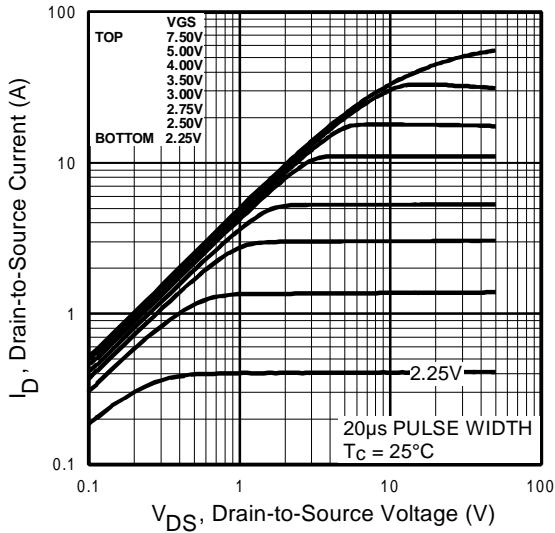
### Notes:

① Repetitive rating; pulse width limited by max. junction temperature. ( See fig. 11 )

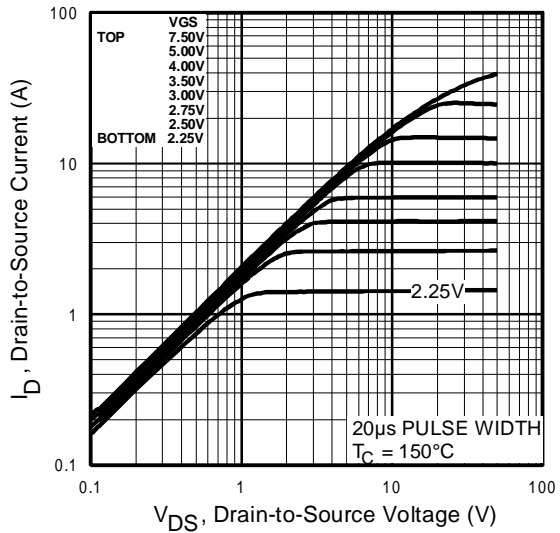
③  $I_{SD} \leq 9.0A, di/dt \leq 120A/\mu s, V_{DD} \leq V_{(BR)DSS}, T_J \leq 150^\circ\text{C}$

②  $V_{DD} = 25V, \text{ starting } T_J = 25^\circ\text{C}, L = 4.6\text{mH}, R_G = 25\Omega, I_{AS} = 9.0A.$  (See Figure 12)

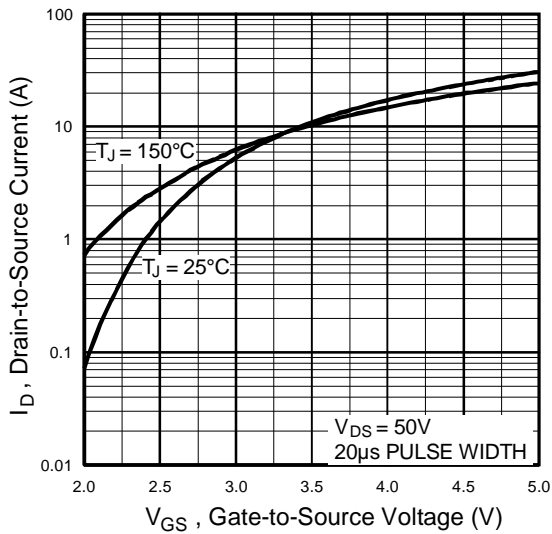
④ Pulse width  $\leq 300\mu s$ ; duty cycle  $\leq 2\%$ .



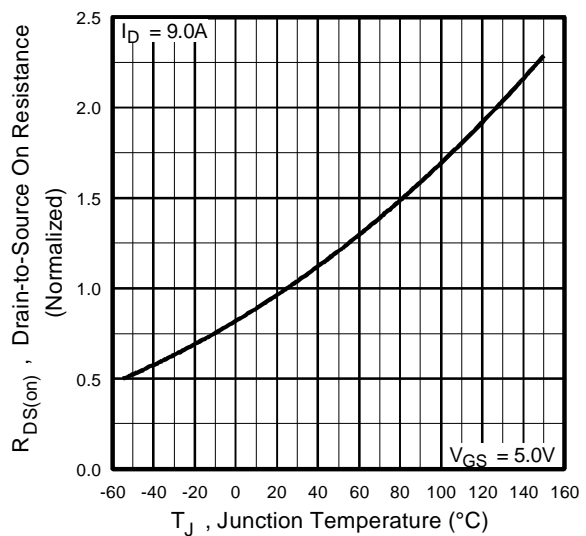
**Fig 1.** Typical Output Characteristics,  
 $T_C = 25^\circ\text{C}$



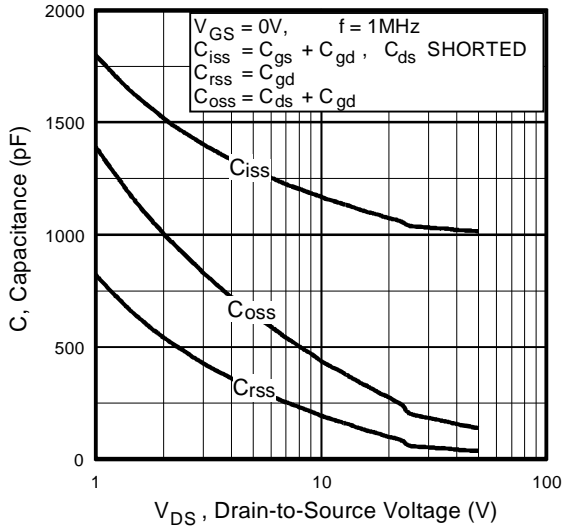
**Fig 2.** Typical Output Characteristics,  
 $T_C = 150^\circ\text{C}$



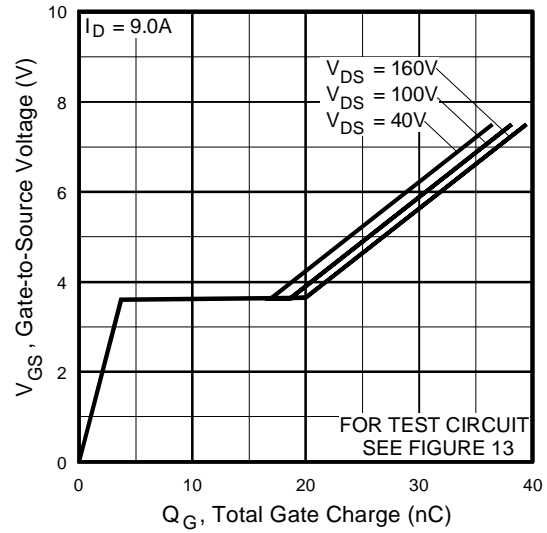
**Fig 3.** Typical Transfer Characteristics



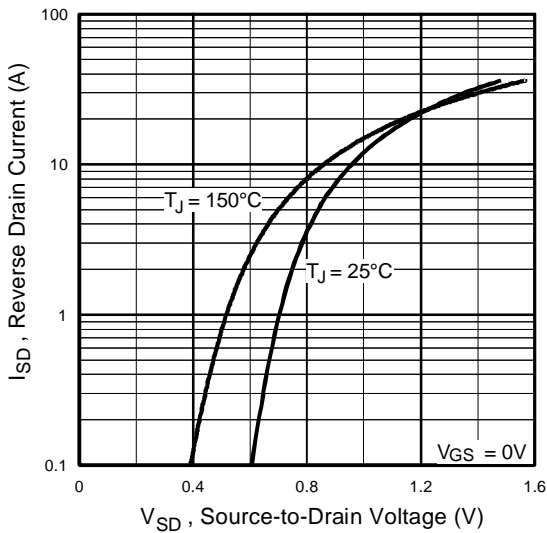
**Fig 4.** Normalized On-Resistance  
Vs. Temperature



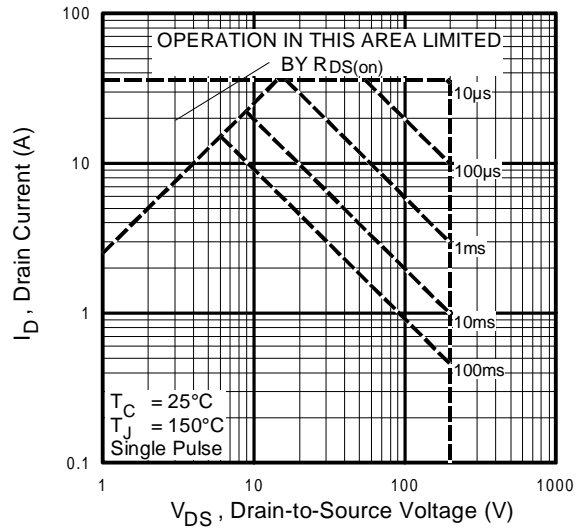
**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage



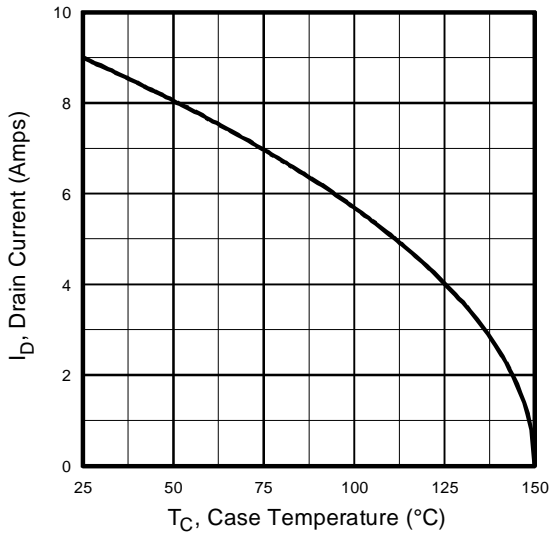
**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage



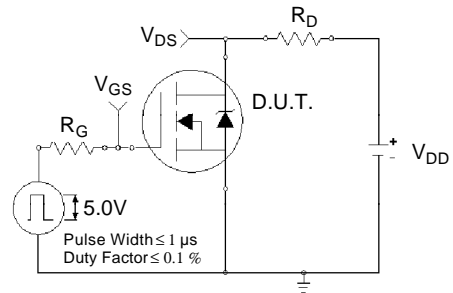
**Fig 7.** Typical Source-Drain Diode Forward Voltage



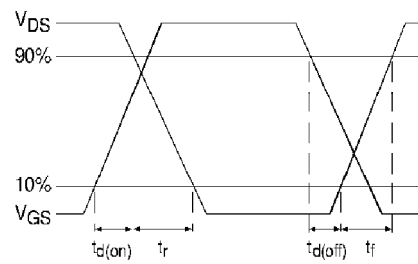
**Fig 8.** Maximum Safe Operating Area



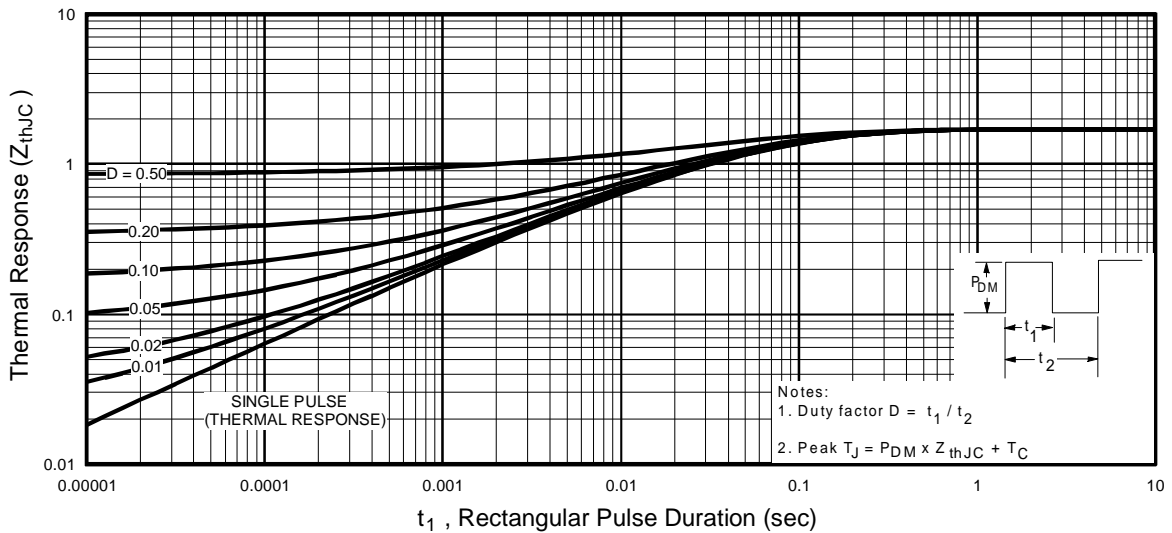
**Fig 9.** Maximum Drain Current Vs. Case Temperature



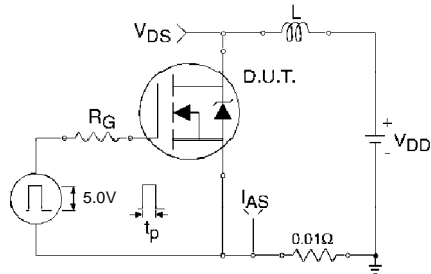
**Fig 10a.** Switching Time Test Circuit



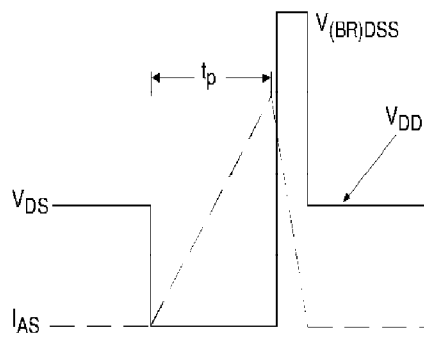
**Fig 10b.** Switching Time Waveforms



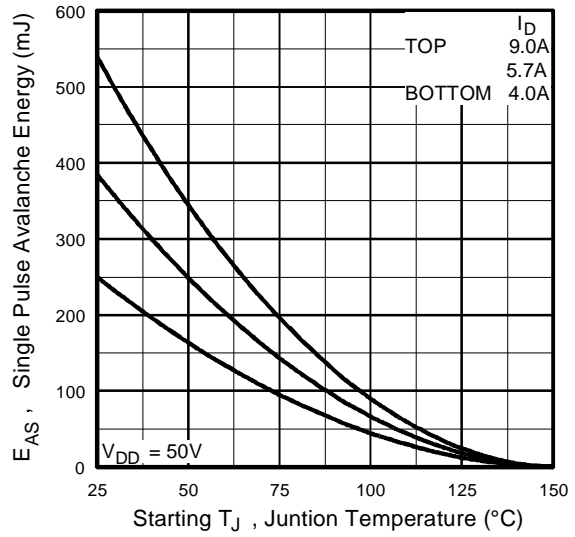
**Fig 11.** Maximum Effective Transient Thermal Impedance, Junction-to-Case



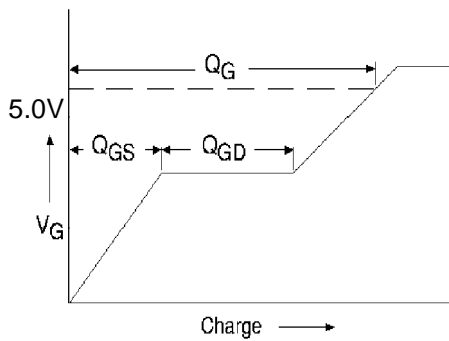
**Fig 12a.** Unclamped Inductive Test Circuit



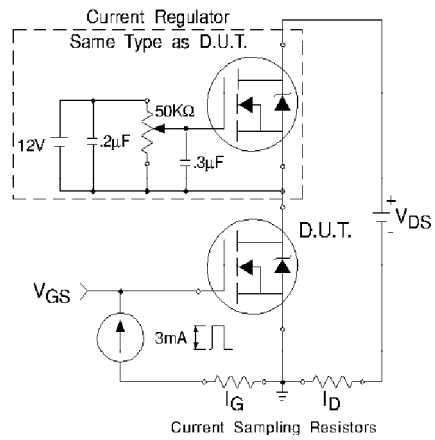
**Fig 12b.** Unclamped Inductive Waveforms



**Fig 12c.** Maximum Avalanche Energy Vs. Drain Current

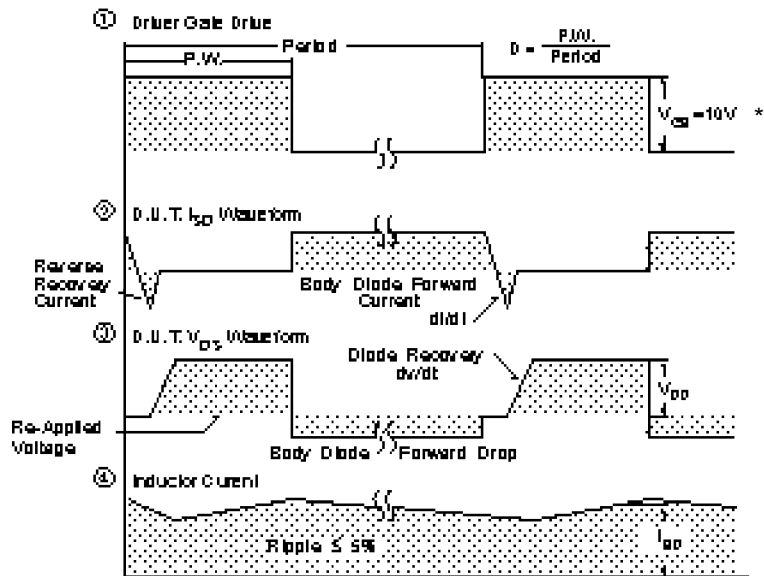
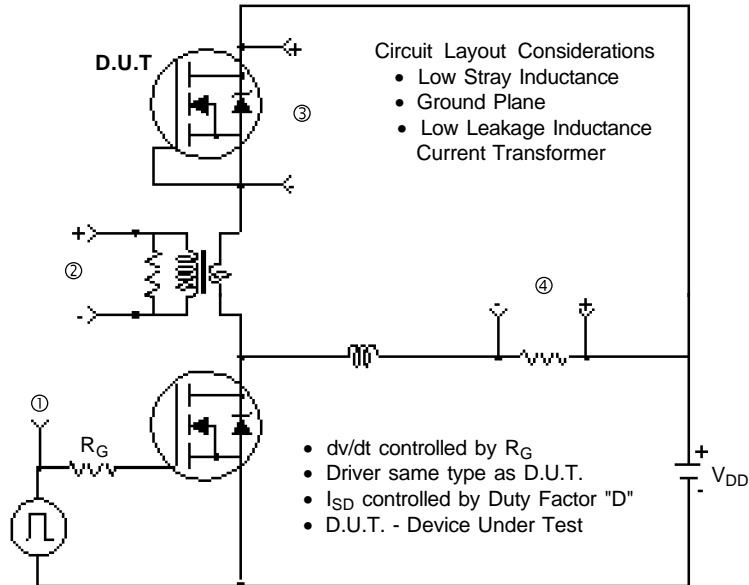


**Fig 13a.** Basic Gate Charge Waveform



**Fig 13b.** Gate Charge Test Circuit

## Peak Diode Recovery dv/dt Test Circuit



\*  $V_{GS} = 5V$  for Logic Level Devices

**Fig 14.** For N-Channel HEXFETS

